

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-2358priority SERIAL NO.
10/624627LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Loan C. Tranpriority FILING DATE
February 10, 2003priority GROUP
2812

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
QU	AA	6,458,666 B2	10-2002	Wasshuber			
QU	AB	6,444,548 B2	09-2002	Divakaruni et al.			
QU	AC	3,886,003	05-1975	Takagi et al.			
QU	AD	4,366,338	12-1982	Turner et al.			
QU	AE	6,008,115	12-1999	Jung			
QU	AF	6,506,647 B2	01-2003	Kuroda et al.			
QU	AG	US2001/0036713A1	11-01-2001	Rodder et al.			July 5, 2001
QU	AH	US2002/0034865A1	03-21-2002	Uimimoto et al.			Nov. 30, 2001
QU	AI	09/876,722		Scott			June 6, 2001
QU	AJ	10/133,193		McQueen et al.			April 26, 2002
	AK						
	AL						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM							
	AN							
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	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

QU	AQ	Young et al., "A 0.13 μ m CMOS Technology with 193 nm Lithography and Cu/Low-k for High Performance Applications", IEDM, pgs. 563-566, April 2000.
QU	AR	Yeh et al., "Optimum Halo Structure for Sub-0.1 μ m CMOSFETs", IEEE Transactions on Electronic Devices, Vol. 48, No. 10, October 2001, pgs. 2357-2362.
QU	AS	Bouillon et al., "Re-examination of Indium implantation for a low power 0.1 μ m technology". IDEM, pgs. 897-900, 1993 (year is sufficient so that date is not in issue).

EXAMINER

James M. Kennedy

DATE CONSIDERED

Feb. 15, 2005

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

4/3 IDS 11/13/03

Form PTO-603		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2358		SERIAL NO. 10/624,627	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px; font-size: 24px; transform: rotate(-45deg);"> OPIE NOV 13 2003 PATENT & TRADEMARK OFFICE </div> </div>					ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small>			
					APPLICANT Luan C. Tran			
					FILING DATE July 21, 2003		GROUP 2811	
U.S. PATENT DOCUMENTS								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
94	AA	6,144,079 A	11-2000	Shirahata et al.				
94	AB	6,033,952	03-2000	Yasumura, et al.				
94	AC	6,124,168	09-2000	Ong				
94	AD	5,688,705	11-1997	Bergemont				
94	AE	5,866,448	02-1999	Pradeep et al.				
94	AF	5,858,847	01-1999	Zhou et al.				
94	AG	6,380,598	04-2002	Chan				
94	AH	6,060,364	05-2000	Maszara et al.				
94	AI	6,194,276 B1	02-2001	Chan et al.				
94	AJ	6,359,319 B1	03-2002	Noda				
94	AK	5,164,806	11-1992	Nagatomo et al.				
94	AL	4,937,756	06-1990	Hsu et al.				
FOREIGN PATENT DOCUMENTS								
	Document Number	Date	Country	Class	Subclass	Translation		
						Yes	No	
94	AM	EP 0718881	06/96	EPO, Chan				
	AN							
	AO							
	AP							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
94	AR	Watanabe, H. et al., Novel 0.44µm ² Ti-Salicide STI Cell Technology for High-Density NOR Flash Memories and High Performance Embedded Application, IEEE 1998, pp. 36.2.1 - 36.2.4.						
94	AS	Wolf, S., "Silicon Processing for the VLSI Era", Vol. 2, pp. 632-635.						
94	AT	MITSUBISHI ELECTRIC WEBSITE: Reprinted from website http://www.mitsubishielectric.com/r_and_d/tech_showcase/ts8.php on 3/29/2001: "8. Production Line Application of a Fine Hole Pattern-Formation Technology for Semiconductors", on 3/29/2001, 4 pgs						
EXAMINER: <i>Jennifer M. Kennedy</i> DATE CONSIDERED: <i>Feb 15, 2005</i>								
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>								

2/3 IDS 11/13/03

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
M122-2358

SERIAL NO.
10624627

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ART CITED BY APPLICANT
(Indicate several sheets if necessary)

APPLICANT
Luan C. Tran

FILING DATE
July 21, 2003

GROUP
2811

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
94	AA 5,930,614	07-1999	Eimori et al.			
94	AB 5,635,744	06-1997	Hidaka et al.			
94	AC 6,204,536	03-2001	Maeda et al.			
94	AD 6,515,899 B1	02-2003	Tu et al.			
94	AE 4,570,331	02-1986	Eaton, Jr. et al.			
94	AF 6,429,079 B1	08-2002	Maeda et al.			
94	AG 6,607,979 B1	08-2003	Kamiyama			
94	AH 4,686,000	08-1987	Heath			
94	AI 5,814,875	09-1998	Kumazaki			
94	AJ 5,654,573	08-1997	Onishi et al.			
94	AK 6,479,330 B2	11-2002	Iwamatsu et al.			
94	AL 6,586,803	07-2003	Hidaka et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

94	AR	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/sep99/docs/feature1.asp on 3/29/2001: "Resists Join the Sub- λ Revolution", 9 pgs.
94	AS	CAHNERS SEMICONDUCTOR INTERNATIONAL WEBSITE: Reprinted from http://www.semiconductor.net/semiconductor/issues/1999/aug99/docs/lithography.asp on 3/29/2001: "Paths to Smaller Features", 1 pg.
94	AT	Wolf, S., "Silicon Processing for the VLSI Era, Vol. 1: Process Technology," Lattice Press 1988, pp. 434-437.

EXAMINER: Jennifer M. Kennedy DATE CONSIDERED Feb. 15, 2005

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3/3 IDS 11/13/03

Sheet 3 of 3

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-2358		SERIAL NO. 10/624,627	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tran			
				FILING DATE July 21, 2003		GROUP 2811	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
94	AA 6,552,401 B1	04-2003	Dennison				
94	AB 6,627,524 B2	09-2003	Scott				
94	AC US2002/0182829A1	12-2002	Chen				
94	AD US2002/0164846A1	11-2002	Lin et al.				
94	AE US2003/0071310A1	04-2003	Salling et al.				
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
94	AR		"Session 18: Integrated Circuits and Manufacturing - DRAM and Embedded DRAM Technology," 2001 IEDM Technical Program, 2001 IEEE International Electron Devices Meeting, Dec. 4, 2001, reprinted 11/15/01 from http://www.his.com/~iedm/techprogram/sessions/s18.html , pp. 1-2.				
	AS						
	AT						
EXAMINER <i>Jennifer M. Kennedy</i> DATE CONSIDERED <i>Feb. 15, 2005</i>							
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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MAR-10-2004 10:23

WELLS ST. JOHN, P.S.

5098383424

P.03/03

Form PTO-149 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M127-2124		SERIAL NO. 10524427	
LIST OF ART CITED BY APPLICANT (In the special column if necessary)				APPLICANT Lutz C. Tress			
FILING DATE July 21, 2003				GROUP 2811			
U.S. PATENT INVENTIONS							
* Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
QU	AM 6,180,468 B1	03-2001	Yu et al.			/	
QU	AB 6,207,510 B1	03-2001	Abeln et al.				
QU	AC US2003/0030112A1	05-2003	Wade et al.				
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EXAMINER: Jennifer M. Kennedy (DO NOT CONSIDER) Feb 13, 2005 *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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APR-16-2004 16:32

WELLS ST. JOHN, P.S.

5098383424 P.03/03

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
31127-2139SERIAL NO.
116524627LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
L. J. C. T. Inc.FILING DATE
July 21, 2003GROUP
2011

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Applicable
QU	AA	5,941,115	11-1998	Ishikawa			
QU	AB	6,331,458 B1	12-2001	Arjman et al.			
QU	AC	6,251,744 B1	08-2001	Se et al.			
	AD						
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FOREIGN PATENT DOCUMENTS

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Jennifer M. Kennedy Feb 15, 2005

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WELLS ST. JOHN, P.S.

5098383424 P. 03/03

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
31122-2333SERIAL NO.
10424 227LIST OF ART CITED BY APPLICANT
(In the several classes if necessary)APPLICANT
Lynn C. TimFILING DATE
July 31, 2003CLASSIFICATION
2831

U.S. PATENT REFERENCES

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
JM	6,521,497	02-2003	Chen et al.			
JM	6,492,694	12-2002	Noble et al.			
JM	6,449,863 B1	10-2002	Yang et al.			
JM	6,451,704 B1	09-2002	Protop et al.			
JM	6,444,747 B1	08-2002	Sagawa et al.			
JM	6,342,034 B1	01-2002	Swafford et al.			
JM	6,277,720 B1	09-2001	Doshi et al.			
JM	5,923,973	07-1999	Rakowski			
JM	5,846,934	02-1999	Kadish et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
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DATE CONSIDERED

James M. Kennedy Feb 15, 2005

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WELLS ST. JOHN, P.S.

5098383424 P.03/03

JAN 11 2005

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M02-2153		SERIAL NO. 10524577	
1. LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Luan C. Tiao		FILING DATE July 21, 2005	
				GROUP 2811			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
GU	AA	5,767,557	06-1998	Kohiyali			
GU	AB	5,360,295	11-1994	Vina			
GU	AC	5,397,909	03-1995	Mouchi			
GU	AD	5,893,728	04-1999	Hidaka			
GU	AE	5,671,526	09-1997	Kawaguchi			
GU	AF	5,325,704	07-1993	Wakamiya et al.			
GU	AG	5,441,161	10-1995	Iwamatsu et al.			
GU	AH	5,333,013	10-1994	Yamaguchi et al.			
GU	AI	5,856,126	01-1999	Wu			
GU	AJ	5,877,056	08-1999	Wu			
GU	AK	6,318,115 B1	02-2003	Boynowski			
GU	AL	6,642,581 B2	11-2003	Matsuda et al.			
GU	AM	6,297,082 H1	10-2001	Lin et al.			
GU	AN	US2002/0103692A1	04-2002	Mocula et al.			
GU	AO	US2003/0189231	10-2003	Cleveland et al.			
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translating	
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
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EXAMINER Jenny M. Kaurieda				DATE CONSIDERED Feb 15, 2005			
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